







**INSTRUMENTS** 

**TMUX7212M** 

JAJSN81 - JANUARY 2024

# TMUX7212M 44 V 低 RON、1:1 (SPST)、4 チャネル高精度スイッチ、ラッチアップ リー、1.87 ロジック

## 1 特長

ラッチアップ耐性

デュアル電源電圧範囲: ±4.5V~ ±22 V

単電源電圧範囲:4.5V~ 44 V -55℃~+125℃の動作温度範囲

低いオン抵抗:2Ω

大電流のサポート: 220mA (最大値)

1.8V ロジック互換

ロジック ピンにプルダウン抵抗を内蔵

フェイルセーフ ロジック

レール ツー レール動作

双方向動作

## 2 アプリケーション

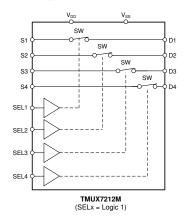
航空用フライト コントロール ユニット

航空機のコックピット ディスプレイ

スタンドアロンの航空用高精度フライト コントロ ール

インターコネクト ディストリビューション ボック ス

航空宇宙および防衛



TMUX7212M ブロック図

## 3 概要

TMUX7212M は、独立して選択できる 4 つの 1 : 1 単極単投 (SPST) スイッチ チャネルを備えた相補型 金属酸化膜半導体 (CMOS) スイッチです。これらの デバイスは、単一電源 (4.5V~44 V)、デュアル電源 (±4.5V~±22 V)、または非対称電源(V<sub>DD</sub> = 12V、V<sub>SS</sub> = -5V など) で動作します。TMUX7212M は、ソース (Sx) およびドレイン (Dx) ピンで、V<sub>SS</sub> から V<sub>DD</sub> まで の範囲の双方向アナログおよびデジタル信号をサポー トします。

TMUX7212M の各スイッチは、SELx ピンで適切な口 ジック制御入力を使用して制御します。TMUX7212M は高精度スイッチおよびマルチプレクサ デバイス フ アミリの製品であり、オンおよびオフ時のリーク電流 が非常に小さいため、高精度の測定用途に使用できま す。

TMUX7212M ファミリはラッチアップ フリーであ るため、過電圧イベントによってよく発生するデバイ ス内の寄生構造間の好ましくない大電流イベントを防 止できます。ラッチアップ状態は通常、電源レールが オフにされるまで継続するため、デバイスの故障の原 因となる場合があります。このラッチアップ フリー という特長により、TMUX7212M スイッチおよびマ ルチプレクサ ファミリは過酷な環境でも使用できま す。さらに、TMUX7212M は、最低 -55℃までの拡張 温度範囲での使用が定格内であるため、過酷な産業用 および航空宇宙のアプリケーションの優れた選択肢で す。

#### パッケージ情報

		* * * * * * * * * * * * * * * * * * *			
部品番号 <sup>(1)</sup>		パッケージ <sup>(2)</sup>	パッケージ サイズ <sup>(3)</sup>		
	TMUX7212M	PW (TSSOP、16)	5mm × 6.4mm		

- (1) セクション 4 を参照
- 詳細については、セクション 12 を参照してください。
- パッケージ サイズ (長さ×幅) は公称値であり、該当する場合 (3) はピンも含まれます。



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## **4 Device Comparison Table**

PRODUCT	DESCRIPTION			
TMUX7212M	Low-Leakage-Current, Precision, 4-Channel, 1:1 (SPST) Switches (Logic High)			



# **5 Pin Configuration and Functions**

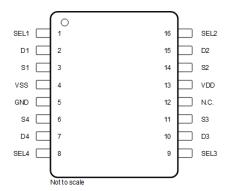


図 5-1. PW Package 16-Pin TSSOP (Top View)

表 5-1. Pin Functions

ı	PIN	TYPE(1)	DESCRIPTION(2)
NAME	NO.	IYPE	DESCRIPTION <sup>(2)</sup>
D1	2	I/O	Drain pin 1. Can be an input or output.
D2	15	I/O	Drain pin 2. Can be an input or output.
D3	10	I/O	Drain pin 3. Can be an input or output.
D4	7	I/O	Drain pin 4. Can be an input or output.
GND	5	Р	Ground (0V) reference
N.C.	12	_	No internal connection. Can be shorted to GND or left floating.
S1	3	I/O	Source pin 1. Can be an input or output.
S2	14	I/O	Source pin 2. Can be an input or output.
S3	11	I/O	Source pin 3. Can be an input or output.
S4	6	I/O	Source pin 4. Can be an input or output.
SEL1	1	1	Logic control input 1, has internal 4MΩ pull-down resistor. Controls channel 1 state as shown in セクション 8.5.
SEL2	16	ı	Logic control input 2, has internal 4MΩ pull-down resistor. Controls channel 2 state as shown in セクション 8.5.
SEL3	9	ı	Logic control input 3, has internal 4MΩ pull-down resistor. Controls channel 3 state as shown in セクション 8.5.
SEL4	8	ı	Logic control input 4, has internal 4MΩ pull-down resistor. Controls channel 4 state as shown in セクション 8.5.
VDD	13	Р	Positive power supply. This pin is the most positive power-supply potential. For reliable operation, connect a decoupling capacitor ranging from 0.1µF to 10µF between V <sub>DD</sub> and GND.
VSS	4	Р	Negative power supply. This pin is the most negative power-supply potential. In single-supply applications, this pin can be connected to ground. For reliable operation, connect a decoupling capacitor ranging from 0.1µF to 10µF between V <sub>SS</sub> and GND.

- (1) I = input, O = output, I/O = input and output, P = power.
- (2) Refer to セクション 8.4 for what to do with unused pins.

English Data Sheet: SCDS456



## **6 Specifications**

## 6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1) (2)

		MIN	MAX	UNIT
V <sub>DD</sub> – V <sub>SS</sub>			48	V
$V_{DD}$	Supply voltage	-0.5	48	V
V <sub>SS</sub>		-48	0.5	V
V <sub>SEL</sub> or V <sub>EN</sub>	Logic control input pin voltage (SELx)	-0.5	48	V
I <sub>SEL</sub> or I <sub>EN</sub>	Logic control input pin current (SELx)	-30	30	mA
V <sub>S</sub> or V <sub>D</sub>	Source or drain voltage (Sx, Dx)	V <sub>SS</sub> -0.5	V <sub>DD</sub> +0.5	V
I <sub>IK</sub>	Diode clamp current <sup>(3)</sup>	-30	30	mA
I <sub>S</sub> or I <sub>D (CONT)</sub>	Source or drain continuous current (Sx, Dx)		I <sub>DC</sub> + 10 % <sup>(4)</sup>	mA
T <sub>A</sub>	Ambient temperature	-55	150	°C
T <sub>stg</sub>	Storage temperature	-65	150	°C
TJ	Junction temperature		150	°C
D	Total power dissipation (QFN) <sup>(5)</sup>		1650	mW
P <sub>tot</sub>	Total power dissipation (TSSOP) <sup>(5)</sup>		700	mW

<sup>(1)</sup> Operation outside the Absolute Maximum Rating may cause permanent device damage. Absolute Maximum Rating do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Condition. If used outside the Recommended Operating Condition but within the Absolute Maximum Rating, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

- (2) All voltages are with respect to ground, unless otherwise specified.
- (3) Pins are diode-clamped to the power-supply rails. Over voltage signals must be voltage and current limited to maximum ratings.
- (4) Refer to Source or Drain Continuous Current table for I<sub>DC</sub> specifications.
- (5) For QFN package: P<sub>tot</sub> derates linearly above T<sub>A</sub> = 70°C by 24.2mW/°C. For TSSOP package: P<sub>tot</sub> = 700 mW (max) and derates linearly above T<sub>A</sub> = 70°C by 10.7mW/°C.

#### 6.2 ESD Ratings

			VALUE	UNIT				
TMUX7212	TMUX7212							
V	Human body model (HBM), per ANSI/ESDA/ JEDEC JS-001, all pins <sup>(1)</sup>		±1500	V				
V <sub>(ESD)</sub>	Electrostatic discharge	Charged device model (CDM), per JEDEC JS-002, all pins <sup>(2)</sup>	±500	V				

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

資料に関するフィードバック(ご意見やお問い合わせ)を送信

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#### **6.3 Thermal Information**

		TMUX7212	
	THERMAL METRIC <sup>(1)</sup>	PW (TSSOP)	UNIT
		16 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	94.5	°C/W
R <sub>0JC(top)</sub>	Junction-to-case (top) thermal resistance	25.5	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	41.1	°C/W
$\Psi_{JT}$	Junction-to-top characterization parameter	1.1	°C/W
$\Psi_{JB}$	Junction-to-board characterization parameter	40.4	°C/W
R <sub>θJC(bot)</sub>	Junction-to-case (bottom) thermal resistance	N/A	°C/W

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

## **6.4 Recommended Operating Conditions**

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
$V_{DD} - V_{SS}$ (1)	Power supply voltage differential	4.5	44	V
$V_{DD}$	Positive power supply voltage	4.5	44	V
V <sub>S</sub> or V <sub>D</sub>	Signal path input/output voltage (source or drain pin) (Sx, D)	V <sub>SS</sub>	$V_{DD}$	V
V <sub>SEL</sub> or V <sub>EN</sub>	Address or enable pin voltage	0	44	V
I <sub>S</sub> or I <sub>D (CONT)</sub>	Source or drain continuous current (Sx, D)		I <sub>DC</sub> <sup>(2)</sup>	mA
T <sub>A</sub>	Ambient temperature	-55	125	°C

 $V_{DD}$  and  $V_{SS}$  can be any value as long as  $4.5V \le (V_{DD} - V_{SS}) \le 44 \text{ V}$ , and the minimum  $V_{DD}$  is met. Refer to *Source or Drain Continuous Current* table for  $I_{DC}$  specifications.

#### 6.5 Source or Drain Continuous Current

at supply voltage of  $V_{DD}$  ± 10%,  $V_{SS}$  ± 10 % (unless otherwise noted)

CONTINU	CONTINUOUS CURRENT PER CHANNEL (I <sub>DC</sub> ) (2)		T <sub>Δ</sub> = 85°C	T <sub>A</sub> = 125°C	UNIT
PACKAGE	TEST CONDITIONS	T <sub>A</sub> = 25°C	1A - 65 C	1A - 125 C	UNIT
	+44 V Dual Supply <sup>(1)</sup>	220	160	100	mA
	±15 V Dual Supply	220	160	100	mA
PW (TSSOP)	+12 V Single Supply	190	130	90	mA
	±5V Dual Supply	170	120	80	mA
	+5V Single Supply	130	90	60	mA

Specified for nominal supply voltage only.

Product Folder Links: TMUX7212M

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Refer to Total power dissipation (Ptot) limits in Absolute Maximum Ratings table that must be followed with maximum continuous current specification.



## ±15 V Dual Supply: Electrical Characteristics

 $V_{DD}$  = +15 V ± 10%,  $V_{SS}$  = -15 V ±10%, GND = 0V (unless otherwise noted) Typical at  $V_{DD}$  = +15 V,  $V_{SS}$  = -15 V,  $V_{A}$  = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT
ANALOG	SWITCH			<u> </u>			
		V <sub>S</sub> = -10 V to +10 V	25°C		2	2.7	Ω
R <sub>ON</sub>	On-resistance	I <sub>D</sub> = -10mA	-40°C to +85°C			3.4	Ω
		Refer to On-Resistance	–55°C to +125°C			4	Ω
		V <sub>S</sub> = -10 V to +10 V	25°C		0.1	0.18	Ω
$\Delta R_{ON}$	On-resistance mismatch between channels	I <sub>D</sub> = -10mA	-40°C to +85°C			0.19	Ω
	STATITOIS .	Refer to On-Resistance	–55°C to +125°C			0.21	Ω
		V <sub>S</sub> = -10 V to +10 V	25°C		0.2	0.46	Ω
R <sub>ON FLAT</sub>	On-resistance flatness	$I_S = -10 \text{mA}$	-40°C to +85°C			0.65	Ω
		Refer to On-Resistance	–55°C to +125°C			0.7	Ω
R <sub>ON DRIFT</sub>	On-resistance drift	V <sub>S</sub> = 0V, I <sub>S</sub> = -10mA Refer to On-Resistance	-55°C to +125°C		0.008		Ω/°C
		$V_{DD}$ = 16.5V, $V_{SS}$ = -16.5V Switch state is off $V_{S}$ = +10 V / -10 V $V_{D}$ = -10 V / + 10 V Refer to Off-Leakage Current	25°C	-0.25	0.05	0.25	nA
le(OFF)	Source off leakage current <sup>(1)</sup>		-40°C to +85°C	-3		3	nA
·5(OFF)	Course on leakage current		–55°C to +125°C	-20		20	nA
		V <sub>DD</sub> = 16.5V, V <sub>SS</sub> = -16.5V	25°C	-0.25	0.05	0.25	nA
RON  ARON  RON FLAT  RON DRIFT  IS(OFF)  IS(OFF)  IS(ON) ID(ON)  LOGIC INI VIH  VIL  IIH  IIIL  CIN  POWER S	Drain off leakage current <sup>(1)</sup>	Switch state is off $V_S = +10 \text{ V} / -10 \text{ V}$	-40°C to +85°C	-3		3	nA
'D(OFF)	Brain on loanage ourron	V <sub>D</sub> = -10 V / + 10 V Refer to Off-Leakage Current	-55°C to +125°C	-20		2.7 3.4 4 0.18 0.19 0.21 0.46 0.65 0.7  0.25 3 20 0.25 3 20 0.4 1 3 44 0.8 1.2	nA
		V <sub>DD</sub> = 16.5V, V <sub>SS</sub> = -16.5V	25°C	-0.4	0.1	0.4	nA
I <sub>S(ON)</sub>	Channel on leakage current <sup>(2)</sup>	Switch state is on $V_S = V_D = \pm 10 \text{ V}$	-40°C to +85°C	-1		2.7 3.4 4 0.18 0.19 0.21 0.46 0.65 0.7  0.25 3 20 0.25 3 20 0.4 1 3 44 0.8 1.2  56 65 80 20 24	nA
ΔR <sub>ON</sub>		Refer to On-Leakage Current	–55°C to +125°C	-3		3	nA
LOGIC IN	PUTS (SEL / EN pins)						
V <sub>IH</sub>	Logic voltage high		–55°C to +125°C	1.3		44	V
V <sub>IL</sub>	Logic voltage low		–55°C to +125°C	0		0.8	V
I <sub>IH</sub>	Input leakage current		–55°C to +125°C		0.4	1.2	μA
I <sub>IL</sub>	Input leakage current		–55°C to +125°C	-0.1	-0.005		μA
C <sub>IN</sub>	Logic input capacitance		–55°C to +125°C		3.5		pF
POWER S	SUPPLY					,	
			25°C		35	56	μΑ
$I_{DD}$	V <sub>DD</sub> supply current	$V_{DD} = 16.5V, V_{SS} = -16.5V$ Logic inputs = 0V, 5V, or $V_{DD}$	-40°C to +85°C			65	μΑ
		J 17	–55°C to +125°C			80	μA
		40.5)///	25°C		5	20	μA
I <sub>SS</sub>	V <sub>SS</sub> supply current	$V_{DD} = 16.5V, V_{SS} = -16.5V$ Logic inputs = 0V, 5V, or $V_{DD}$	-40°C to +85°C			24	μΑ
		0 1,,	–55°C to +125°C			35	μA

 <sup>(1)</sup> When V<sub>S</sub> is positive, V<sub>D</sub> is negative, or when V<sub>S</sub> is negative, V<sub>D</sub> is positive.
 (2) When V<sub>S</sub> is at a voltage potential, V<sub>D</sub> is floating, or when V<sub>D</sub> is at a voltage potential, V<sub>S</sub> is floating.



## ±15 V Dual Supply: Switching Characteristics

 $V_{DD} = +15 \text{ V} \pm 10\%, \ V_{SS} = -15 \text{ V} \pm 10\%, \ \text{GND} = 0 \text{V} \ \text{(unless otherwise noted)}$  Typical at  $V_{DD} = +15 \text{ V}, \ V_{SS} = -15 \text{ V}, \ T_A = 25^{\circ}\text{C} \ \text{(unless otherwise noted)}$ 

	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT
		V <sub>S</sub> = 10 V	25°C		100	175	ns
t <sub>ON</sub>	Turn-on time from control input	$R_L = 300 \Omega$ , $C_L = 35pF$ Refer to Turn-on and Turn-off	–40°C to +85°C			205	ns
		Time	–55°C to +125°C			225	ns
		V <sub>S</sub> = 10 V	25°C		80	205	ns
t <sub>OFF</sub>	Turn-off time from control input	$R_L = 300 \Omega$ , $C_L = 35pF$ Refer to Turn-on and Turn-off	-40°C to +85°C			225	ns
		Time	–55°C to +125°C			175 205 225 205 225 240 7 3 3 3 0	ns
	D : ( "	V <sub>DD</sub> rise time = 1 μs	25°C		0.17		ms
t <sub>ON (VDD)</sub>	Device turn on time (V <sub>DD</sub> to output)	$R_L = 300 \Omega, C_L = 35pF$	–40°C to +85°C		0.18		ms
	7	Refer to Turn-on (VDD) Time	–55°C to +125°C		100  80  0.17  0.18  0.18  260  60  -70  -50  -114  -93  56  -0.15  -68		ms
t <sub>PD</sub>	Propagation delay	$R_L$ = 50 $\Omega$ , $C_L$ = 5pF Refer to Propagation Delay	25°C		260		ps
Q <sub>INJ</sub>	Charge injection	V <sub>S</sub> = 0V, C <sub>L</sub> = 100pF Refer to Charge Injection	25°C		60		рС
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 0V$ , $f = 100kHz$ Refer to Off Isolation	25°C		-70		dB
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 0V$ , $f = 1MHz$ Refer to Off Isolation	25°C		-50		dB
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 0V$ , $f = 100kHz$ Refer to Crosstalk	25°C		-114		dB
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 0V$ , $f = 1MHz$ Refer to Crosstalk	25°C		-93		dB
BW	-3dB Bandwidth	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 0V$ Refer to Bandwidth	25°C		56		MHz
IL	Insertion loss	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 0V$ , $f = 1MHz$	25°C		-0.15		dB
ACPSRR	AC Power Supply Rejection Ratio	$V_{PP}$ = 0.62 V on $V_{DD}$ and $V_{SS}$ $R_L$ = 50 $\Omega$ , $C_L$ = 5pF, $f$ = 1MHz Refer to ACPSRR	25°C		-68		dB
THD+N	Total Harmonic Distortion + Noise	$V_{PP}$ = 15 V, $V_{BIAS}$ = 0V $R_L$ = 10k $\Omega$ , $C_L$ = 5pF, f = 20Hz to 20kHz Refer to THD + Noise	25°C	0	.0004		%
C <sub>S(OFF)</sub>	Source off capacitance	V <sub>S</sub> = 0V, f = 1MHz	25°C		28		pF
C <sub>D(OFF)</sub>	Drain off capacitance	V <sub>S</sub> = 0V, f = 1MHz	25°C		45		pF
C <sub>S(ON),</sub> C <sub>D(ON)</sub>	On capacitance	V <sub>S</sub> = 0V, f = 1MHz	25°C		145		pF

Product Folder Links: TMUX7212M

資料に関するフィードバック(ご意見やお問い合わせ)を送信



## ±20 V Dual Supply: Electrical Characteristics

 $V_{DD} = +20 \text{ V} \pm 10\%, \ V_{SS} = -20 \text{ V} \pm 10\%, \ \text{GND} = 0 \text{V} \ \text{(unless otherwise noted)}$  Typical at  $V_{DD} = +20 \text{ V}, \ V_{SS} = -20 \text{ V}, \ T_A = 25 ^{\circ}\text{C} \ \text{(unless otherwise noted)}$ 

• .	$\frac{v_{DD} - +20 \text{ v, } v_{SS}20 \text{ v, } v_{A}20 \text{ v, } $	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
		V <sub>S</sub> = -15 V to +15 V	25°C		1.7	2.5	Ω
R <sub>ON</sub>	On-resistance	$I_D = -10 \text{ mA}$	-40°C to +85°C			3	Ω
		Refer to On-Resistance	-55°C to +125°C			3.6	Ω
		V <sub>S</sub> = -15 V to +15 V	25°C		0.1	0.18	Ω
$\Delta R_{ON}$	On-resistance mismatch between channels	$I_D = -10 \text{mA}$	-40°C to +85°C			0.19	Ω
	ond more	Refer to On-Resistance	–55°C to +125°C			0.21	Ω
		V <sub>S</sub> = -15 V to +15 V	25°C		0.3	0.6	Ω
R <sub>ON FLAT</sub>	On-resistance flatness	$I_S = -10 \text{mA}$	-40°C to +85°C			0.8	Ω
		Refer to On-Resistance	-55°C to +125°C			0.95	Ω
R <sub>ON DRIFT</sub>	On-resistance drift	V <sub>S</sub> = 0V, I <sub>S</sub> = -10mA Refer to On-Resistance	–55°C to +125°C		0.008		Ω/°C
	OFF) Source off leakage current <sup>(1)</sup>	$V_{DD}$ = 22 V, $V_{SS}$ = -22 V Switch state is off $V_{S}$ = +15 V / -15 V $V_{D}$ = -15 V / + 15 V Refer to Off-Leakage Current	25°C	-1	0.05	1	nA
lovers			-40°C to +85°C	-4.5		4.5	nA
'S(OFF)			–55°C to +125°C	-33		33	nA
I <sub>S(OFF)</sub> I <sub>D(OFF)</sub> I <sub>S(ON)</sub> I <sub>D(ON)</sub> LOGIC INF	Drain off leakage current <sup>(1)</sup>	$V_{DD} = 22 \text{ V}, V_{SS} = -22 \text{ V}$ Switch state is off $V_{S} = +15 \text{ V} / -15 \text{ V}$	25°C	-1	0.1	1	nA
			-40°C to +85°C	-4.5		4.5	nA
'D(OFF)	Drain on leakage current	V <sub>D</sub> = -15 V / + 15 V Refer to Off-Leakage Current	–55°C to +125°C	-33		33	nA
		V <sub>DD</sub> = 22 V, V <sub>SS</sub> = -22 V	25°C	-1 0.1 1 +85°C -4.5 4.5 +125°C -33 33 -1 0.1 1 +85°C -1.5 1.5	1	nA	
. ' '	Channel on leakage current <sup>(2)</sup>	Switch state is on $V_S = V_D = \pm 15 \text{ V}$	-40°C to +85°C	-1.5		2.5 3 3.6 0.18 0.19 0.21 0.6 0.8 0.95 1 4.5 33	nA
ARON  RON FLAT  RON DRIFT  IS(OFF)  IS(OFF)  ID(OFF)  IUD(OFF)  IUD(ON)  LOGIC INP  VIH  IUD  IIH  IIIL  IUD  POWER SL		Refer to On-Leakage Current	-55°C to +125°C	-8		8	nA
LOGIC IN	PUTS (SEL / EN pins)						
V <sub>IH</sub>	Logic voltage high		-55°C to +125°C	1.3		44	V
V <sub>IL</sub>	Logic voltage low		-55°C to +125°C	0		0.8	V
I <sub>IH</sub>	Input leakage current		–55°C to +125°C		0.4	1.2	μA
I <sub>IL</sub>	Input leakage current		-55°C to +125°C	-0.1	-0.005		μA
C <sub>IN</sub>	Logic input capacitance		-55°C to +125°C		3.5		pF
POWER S	SUPPLY						
			25°C		33	65	μΑ
$I_{DD}$	V <sub>DD</sub> supply current	$V_{DD}$ = 22 V, $V_{SS}$ = -22 V Logic inputs = 0V, 5V, or $V_{DD}$	-40°C to +85°C			74	μΑ
			–55°C to +125°C			.7 2.5 3 3.6 0.1 0.18 0.19 0.21 0.3 0.6 0.8 0.95 08 0.5 1 4.5 33 0.1 1 4.5 33 0.1 1 1.5 8 0.4 1.2 0.5 3.5 74 90 7 26 30 3	μA
			25°C		0.2  0.3  0.9  0.008  -1  0.05  .5  4.  33  -1  0.1  .5  4.  0  0.4  1.  -1  -0.005  3.5   33  6  7  9  7  2  3	26	μA
I <sub>SS</sub>	V <sub>SS</sub> supply current	$V_{DD}$ = 22 V, $V_{SS}$ = -22 V Logic inputs = 0V, 5V, or $V_{DD}$	-40°C to +85°C			30	μΑ
			–55°C to +125°C			45	μΑ

When  $V_{\mbox{\scriptsize S}}$  is positive,  $V_{\mbox{\scriptsize D}}$  is negative, or when  $V_{\mbox{\scriptsize S}}$  is negative,  $V_{\mbox{\scriptsize D}}$  is positive.

When  $V_S$  is at a voltage potential,  $V_D$  is floating, or when  $V_D$  is at a voltage potential,  $V_S$  is floating.



## ±20 V Dual Supply: Switching Characteristics

 $V_{DD}$  = +20 V ± 10%,  $V_{SS}$  = -20 V ±10%, GND = 0V (unless otherwise noted) Typical at  $V_{DD}$  = +20 V,  $V_{SS}$  = -20 V,  $V_{A}$  = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT
		V <sub>S</sub> = 10 V	25°C		100	185	ns
t <sub>ON</sub>	Turn-on time from control input	$R_L = 300 \Omega$ , $C_L = 35pF$ Refer to Turn-on and Turn-off	–40°C to +85°C			210	ns
		Time	–55°C to +125°C			230	ns
		V <sub>S</sub> = 10 V	25°C		90	210	ns
t <sub>OFF</sub>	Turn-off time from control input	$R_L = 300 \Omega$ , $C_L = 35pF$ Refer to Turn-on and Turn-off	–40°C to +85°C			225	ns
		Time	–55°C to +125°C			235	ns
		V <sub>DD</sub> rise time = 1 μs	25°C		0.17		ms
t <sub>ON (VDD)</sub>	Device turn on time (V <sub>DD</sub> to output)	$R_L = 300 \Omega, C_L = 35pF$	–40°C to +85°C		0.18		ms
ON (VDD)	(VDD to output)	Refer to Turn-on (VDD) Time	–55°C to +125°C		0.18		ms
t <sub>PD</sub>	Propagation delay	$R_L = 50 \Omega$ , $C_L = 5pF$ Refer to Propagation Delay	25°C		260		ps
Q <sub>INJ</sub>	Charge injection	V <sub>S</sub> = 0V, C <sub>L</sub> = 100pF Refer to Charge Injection	25°C		92		рС
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 0V$ , $f = 100kHz$ Refer to Off Isolation	25°C		-70		dB
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 0V$ , $f = 1MHz$ Refer to Off Isolation	25°C	-50			dB
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 0V$ , $f = 100kHz$ Refer to Crosstalk	25°C	-112			dB
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 0V$ , $f = 1MHz$ Refer to Crosstalk	25°C	-93			dB
BW	–3dB Bandwidth	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 0V$ Refer to Bandwidth	25°C		48		MHz
IL	Insertion loss	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 0V$ , $f = 1MHz$	25°C		-0.14		dB
ACPSRR	AC Power Supply Rejection Ratio	$V_{PP}$ = 0.62 V on $V_{DD}$ and $V_{SS}$ $R_L$ = 50 $\Omega$ , $C_L$ = 5pF, $f$ = 1MHz Refer to ACPSRR	25°C	-68			dB
THD+N	Total Harmonic Distortion + Noise	$V_{PP}$ = 20 V, $V_{BIAS}$ = 0V $R_{L}$ = 10k $\Omega$ , $C_{L}$ = 5pF, f = 20Hz to 20kHz Refer to THD + Noise	25°C	0.0003			%
C <sub>S(OFF)</sub>	Source off capacitance	V <sub>S</sub> = 0V, f = 1MHz	25°C		28		pF
C <sub>D(OFF)</sub>	Drain off capacitance	V <sub>S</sub> = 0V, f = 1MHz	25°C		45		pF
C <sub>S(ON),</sub> C <sub>D(ON)</sub>	On capacitance	V <sub>S</sub> = 0V, f = 1MHz	25°C		145		pF

Product Folder Links: TMUX7212M

資料に関するフィードバック(ご意見やお問い合わせ)を送信



## 44 V Single Supply: Electrical Characteristics

 $V_{DD}$  = +44 V,  $V_{SS}$  = 0V, GND = 0V (unless otherwise noted) Typical at  $V_{DD}$  = +44 V,  $V_{SS}$  = 0V,  $T_A$  = 25°C (unless otherwise noted)

Typical at	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
		V <sub>S</sub> = 0V to 40 V	25°C		2	2.4	Ω
R <sub>ON</sub>	On-resistance	$I_D = -10 \text{mA}$	–40°C to +85°C			3.2	Ω
		Refer to On-Resistance	–55°C to +125°C			3.8	Ω
ΔR <sub>ON</sub>		V <sub>S</sub> = 0V to 40 V	25°C		0.1	0.18	Ω
	On-resistance mismatch between channels	$I_D = -10 \text{mA}$	–40°C to +85°C			0.19	Ω
	onarmois .	Refer to On-Resistance	–55°C to +125°C			0.21	Ω
		V <sub>S</sub> = 0V to 40 V	25°C		0.65	0.8	Ω
R <sub>ON FLAT</sub>	On-resistance flatness	$I_D = -10 \text{mA}$	–40°C to +85°C			1.1	Ω
		Refer to On-Resistance	–55°C to +125°C			1.2	Ω
R <sub>ON DRIFT</sub>	On-resistance drift	V <sub>S</sub> = 22 V, I <sub>S</sub> = -10mA Refer to On-Resistance	–55°C to +125°C		0.007		Ω/°C
		V <sub>DD</sub> = 44 V, V <sub>SS</sub> = 0V	25°C	-1	0.05	1	nA
la comm	Source off leakage current <sup>(1)</sup>	Switch state is off V <sub>S</sub> = 40 V / 1V	–40°C to +85°C	-7		7	nA
I <sub>S(OFF)</sub>		V <sub>D</sub> = 1V / 40 V Refer to Off-Leakage Current	–55°C to +125°C	-50		50	nA
	Drain off leakage current <sup>(1)</sup>	$V_{DD}$ = 44 V, $V_{SS}$ = 0V Switch state is off $V_{S}$ = 40 V / 1V $V_{D}$ = 1V / 40 V Refer to Off-Leakage Current	25°C	-1	0.05	1	nA
In (ore)			–40°C to +85°C	-7		7	nA
I <sub>D(OFF)</sub>			–55°C to +125°C	-50		50	nA
		V <sub>DD</sub> = 44 V, V <sub>SS</sub> = 0V	25°C	-1	0.05	1	nA
I <sub>S(ON)</sub>	Channel on leakage current <sup>(2)</sup>	Switch state is on $V_S = V_D = 40 \text{ V or } 1\text{V}$	–40°C to +85°C	-3.5		3.5	nA
I <sub>D(ON)</sub>		Refer to On-Leakage Current	–55°C to +125°C	-5		5	nA
LOGIC IN	PUTS (SEL / EN pins)						
V <sub>IH</sub>	Logic voltage high		–55°C to +125°C	1.3		44	V
V <sub>IL</sub>	Logic voltage low		–55°C to +125°C	0		0.8	V
I <sub>IH</sub>	Input leakage current		-55°C to +125°C		0.6	1.2	μA
I <sub>IL</sub>	Input leakage current		-55°C to +125°C	-0.1	-0.005		μA
C <sub>IN</sub>	Logic input capacitance		–55°C to +125°C		3.5		pF
POWER S	BUPPLY			•		'	
			25°C		44	79	μΑ
I <sub>DD</sub>	V <sub>DD</sub> supply current	$V_{DD}$ = 44 V, $V_{SS}$ = 0V Logic inputs = 0V, 5V, or $V_{DD}$	–40°C to +85°C			88	μΑ
		Jp, o ., o UD	–55°C to +125°C			105	μΑ

<sup>(1)</sup> When  $V_S$  is positive,  $V_D$  is negative, or when  $V_S$  is negative,  $V_D$  is positive.

When  $V_S$  is at a voltage potential,  $V_D$  is floating, or when  $V_D$  is at a voltage potential,  $V_S$  is floating.

## 44 V Single Supply: Switching Characteristics

 $V_{DD}$  = +44 V,  $V_{SS}$  = 0V, GND = 0V (unless otherwise noted) Typical at  $V_{DD}$  = +44 V,  $V_{SS}$  = 0V,  $T_A$  = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN TYP	P MAX	UNIT
		V <sub>S</sub> = 18 V	25°C	80	) 185	ns
t <sub>ON</sub>	Turn-on time from control input	$R_L = 300 \Omega$ , $C_L = 35pF$ Refer to Turn-on and Turn-off	-40°C to +85°C		205	ns
		Time	-55°C to +125°C		225	ns
		V <sub>S</sub> = 18 V	25°C	90	205	ns
t <sub>OFF</sub>	Turn-off time from control input	$R_L = 300 \Omega$ , $C_L = 35pF$ Refer to Turn-on and Turn-off	-40°C to +85°C		220	ns
		Time	-55°C to +125°C		228	ns
		V <sub>DD</sub> rise time = 1 μs	25°C	0.14	1	ns ns ns ns ns ns ms ms ms ps pC dB dB dB dB dB dB dB pF pF
t <sub>ON (VDD)</sub>	Device turn on time (V <sub>DD</sub> to output)	$R_L = 300 \Omega, C_L = 35pF$	-40°C to +85°C	0.19	5	ms
ON (ADD)	(VDD to output)	Refer to Turn-on (VDD) Time	-55°C to +125°C	0.19	5	ms
t <sub>PD</sub>	Propagation delay	$R_L$ = 50 $\Omega$ , $C_L$ = 5pF Refer to Propagation Delay	25°C	270	)	ps
Q <sub>INJ</sub>	Charge injection	V <sub>S</sub> = 22 V, C <sub>L</sub> = 100pF Refer to Charge Injection	25°C	104	1	рС
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 6V$ , $f = 100kHz$ Refer to Off Isolation	25°C	-70	)	dB
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 6V$ , $f = 1MHz$ Refer to Off Isolation	25°C	-50	)	dB
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 6V$ , $f = 100kHz$ Refer to Crosstalk	25°C	-112	2	dB
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 6V$ , $f = 1MHz$ Refer to Crosstalk	25°C	-93	3	dB
BW	–3dB Bandwidth	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 6V$ Refer to Bandwidth	25°C	46	5	MHz
IL	Insertion loss	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 6V$ , $f = 1MHz$	25°C	-0.1	5	dB
ACPSRR	AC Power Supply Rejection Ratio	$V_{PP}$ = 0.62 V on $V_{DD}$ and $V_{SS}$ $R_L$ = 50 $\Omega$ , $C_L$ = 5pF, $f$ = 1MHz Refer to ACPSRR	25°C	-60	3	dB
THD+N	Total Harmonic Distortion + Noise	$V_{PP}$ = 22 V, $V_{BIAS}$ = 22 V $R_{L}$ = 10k $\Omega$ , $C_{L}$ = 5pF, f = 20Hz to 20kHz Refer to THD + Noise	25°C	0.0003		%
C <sub>S(OFF)</sub>	Source off capacitance	V <sub>S</sub> = 22 V, f = 1MHz	25°C	28	3	pF
C <sub>D(OFF)</sub>	Drain off capacitance	V <sub>S</sub> = 22 V, f = 1MHz	25°C	45	5	pF
C <sub>S(ON),</sub> C <sub>D(ON)</sub>	On capacitance	V <sub>S</sub> = 22 V, f = 1MHz	25°C	149	5	pF

Product Folder Links: TMUX7212M

資料に関するフィードバック(ご意見やお問い合わせ)を送信

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## 12 V Single Supply: Electrical Characteristics

 $V_{DD}$  = +12 V ± 10%,  $V_{SS}$  = 0V, GND = 0V (unless otherwise noted) Typical at  $V_{DD}$  = +12 V,  $V_{SS}$  = 0V,  $T_A$  = 25°C (unless otherwise noted)

	$\frac{V_{DD} = +12 \text{ V, } V_{SS} = 0 \text{ V, } I_A = 25}{\text{PARAMETER}}$	TEST CONDITIONS	TA	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
		V <sub>S</sub> = 0V to 10 V	25°C		2.8	5.4	Ω
R <sub>ON</sub>	On-resistance	$I_D = -10 \text{mA}$	–40°C to +85°C			6.8	Ω
		Refer to On-Resistance	–55°C to +125°C			7.4	Ω
		V <sub>S</sub> = 0V to 10 V	25°C		0.13	0.21	Ω
$\Delta R_{ON}$	On-resistance mismatch between channels	I <sub>D</sub> = -10mA	–40°C to +85°C			0.23	Ω
	ondrinois .	Refer to On-Resistance	–55°C to +125°C			0.25	Ω
		V <sub>S</sub> = 0V to 10 V	25°C		1	1.7	Ω
R <sub>ON FLAT</sub>	On-resistance flatness	I <sub>S</sub> = -10mA	–40°C to +85°C			1.9	Ω
		Refer to On-Resistance	–55°C to +125°C			2	Ω
R <sub>ON DRIFT</sub>	On-resistance drift	V <sub>S</sub> = 6V, I <sub>S</sub> = -10mA Refer to On-Resistance	–55°C to +125°C		0.015		Ω/°C
		V <sub>DD</sub> = 13.2V, V <sub>SS</sub> = 0V	25°C	-0.25	0.01	0.25	nA
I <sub>S(OFF)</sub>	Source off leakage current <sup>(1)</sup>	Switch state is off V <sub>S</sub> = 10 V / 1V	–40°C to +85°C	-2		2	nA
'S(OFF)		V <sub>D</sub> = 1V / 10 V Refer to Off-Leakage Current	–55°C to +125°C	-16		16	nA
	Drain off leakage current <sup>(1)</sup>	, 33	25°C	-0.25	0.05	0.25	nA
I <sub>D(OFF)</sub>		Switch state is off V <sub>S</sub> = 10 V / 1V	–40°C to +85°C	-2		2	nA
·D(OFF)		V <sub>D</sub> = 1V / 10 V Refer to Off-Leakage Current	–55°C to +125°C	-16		16	nA
		V <sub>DD</sub> = 13.2V, V <sub>SS</sub> = 0V	25°C	-0.5	0.05	0.5	nA
I <sub>S(ON)</sub> I <sub>D(ON)</sub>	Channel on leakage current <sup>(2)</sup>	Switch state is on $V_S = V_D = 10 \text{ V or } 1\text{V}$	–40°C to +85°C	-1		1	nA
ים(טא)		Refer to On-Leakage Current	–55°C to +125°C	-3		3	nA
LOGIC IN	PUTS (SEL / EN pins)		-				
V <sub>IH</sub>	Logic voltage high		–55°C to +125°C	1.3		44	٧
V <sub>IL</sub>	Logic voltage low		–55°C to +125°C	0		8.0	V
I <sub>IH</sub>	Input leakage current		–55°C to +125°C		0.4	1.2	μA
I <sub>IL</sub>	Input leakage current		–55°C to +125°C	-0.1	-0.005		μA
C <sub>IN</sub>	Logic input capacitance		–55°C to +125°C		3.5		pF
POWER S	SUPPLY						
		40.01/1/	25°C		30	44	μΑ
$I_{DD}$	V <sub>DD</sub> supply current	$V_{DD}$ = 13.2V, $V_{SS}$ = 0V Logic inputs = 0V, 5V, or $V_{DD}$	-40°C to +85°C			52	μΑ
		0 1 - , - , - 00	–55°C to +125°C			62	μA

<sup>(1)</sup> When  $V_S$  is positive,  $V_D$  is negative, or when  $V_S$  is negative,  $V_D$  is positive.

When  $V_S$  is at a voltage potential,  $V_D$  is floating, or when  $V_D$  is at a voltage potential,  $V_S$  is floating.

## 12 V Single Supply: Switching Characteristics

 $\label{eq:vdd} \begin{array}{l} V_{DD} = +12~V \pm 10\%,~V_{SS} = 0 \text{V, GND} = 0 \text{V (unless otherwise noted)} \\ \hline \text{Typical at V}_{DD} = +12~V,~V_{SS} = 0 \text{V, T}_{A} = 25 ^{\circ}\text{C} \quad \text{(unless otherwise noted)} \end{array}$ 

71	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT
		V <sub>S</sub> = 8V	25°C		170	225	ns
t <sub>ON</sub>	Turn-on time from control input	$R_L = 300 \Omega$ , $C_L = 35pF$ Refer to Turn-on and Turn-off	-40°C to +85°C			276	ns
		Time	-55°C to +125°C			315	ns
		V <sub>S</sub> = 8V	25°C		75	248	ns
t <sub>OFF</sub>	Turn-off time from control input	$R_L = 300 \Omega$ , $C_L = 35pF$ Refer to Turn-on and Turn-off	-40°C to +85°C		-	285	ns
		Time	-55°C to +125°C			310	ns
		V <sub>DD</sub> rise time = 1 μs	25°C		0.17		ms
t <sub>ON (VDD)</sub>	Device turn on time (V <sub>DD</sub> to output)	$R_L = 300 \Omega, C_L = 35pF$	-40°C to +85°C		0.18		ms
	(VDD to output)	Refer to Turn-on (VDD) Time	–55°C to +125°C		0.18		ms
t <sub>PD</sub>	Propagation delay	$R_L = 50 \Omega$ , $C_L = 5pF$ Refer to Propagation Delay	25°C		270		ps
Q <sub>INJ</sub>	Charge injection	V <sub>S</sub> = 6V, C <sub>L</sub> = 100pF Refer to Charge Injection	25°C		12		рС
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 6V$ , $f = 100kHz$ Refer to Off Isolation	25°C		-70		dB
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 6V$ , $f = 1MHz$ Refer to Off Isolation	25°C	-50			dB
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 6V$ , $f = 100kHz$ Refer to Crosstalk	25°C		-112		dB
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 6V$ , $f = 1MHz$ Refer to Crosstalk	25°C		-93		dB
BW	-3dB Bandwidth	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 6V$ Refer to Bandwidth	25°C		125		MHz
IL	Insertion loss	$R_L = 50 \Omega$ , $C_L = 5pF$ $V_S = 6V$ , $f = 1MHz$	25°C		-0.25		dB
ACPSRR	AC Power Supply Rejection Ratio	$V_{PP}$ = 0.62 V on $V_{DD}$ and $V_{SS}$ $R_L$ = 50 $\Omega$ , $C_L$ = 5pF, $f$ = 1MHz Refer to ACPSRR	25°C	-70			dB
THD+N	Total Harmonic Distortion + Noise	$V_{PP}$ = 6V, $V_{BIAS}$ = 6V $R_{L}$ = 10k $\Omega$ , $C_{L}$ = 5pF, f = 20Hz to 20kHz Refer to THD + Noise	25°C	0.001			%
C <sub>S(OFF)</sub>	Source off capacitance	V <sub>S</sub> = 6V, f = 1MHz	25°C		35		pF
C <sub>D(OFF)</sub>	Drain off capacitance	V <sub>S</sub> = 6V, f = 1MHz	25°C		50		pF
C <sub>S(ON)</sub> , C <sub>D(ON)</sub>	On capacitance	V <sub>S</sub> = 6V, f = 1MHz	25°C		145		pF

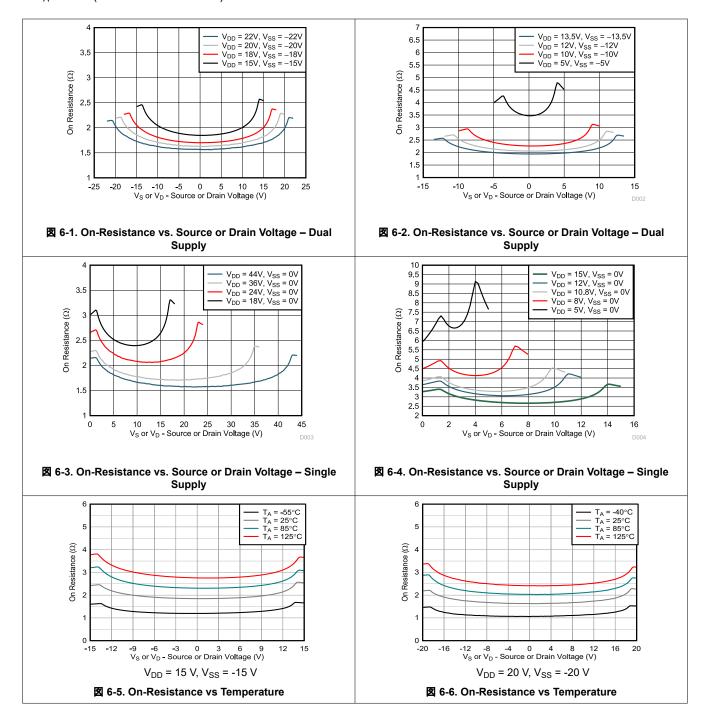
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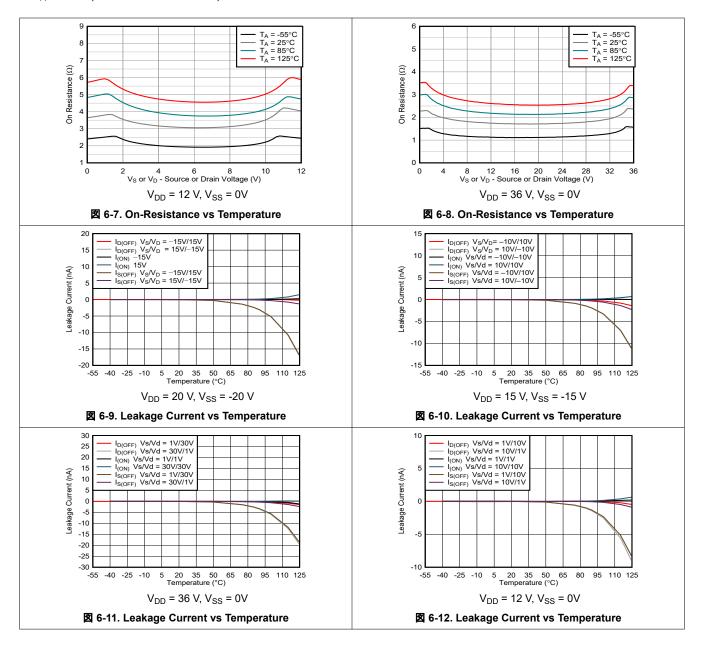
#### 6.6 Typical Characteristics

at T<sub>A</sub> = 25°C (unless otherwise noted)





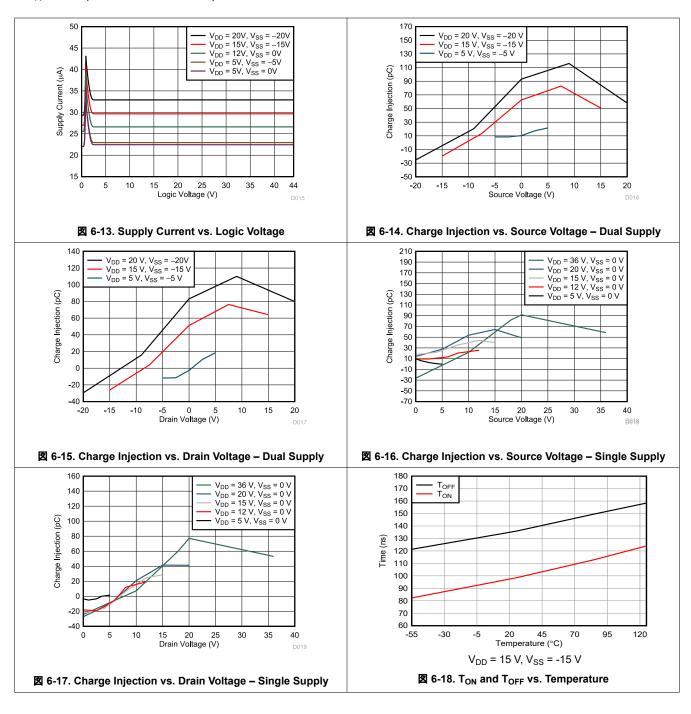
at T<sub>A</sub> = 25°C (unless otherwise noted)



English Data Sheet: SCDS456

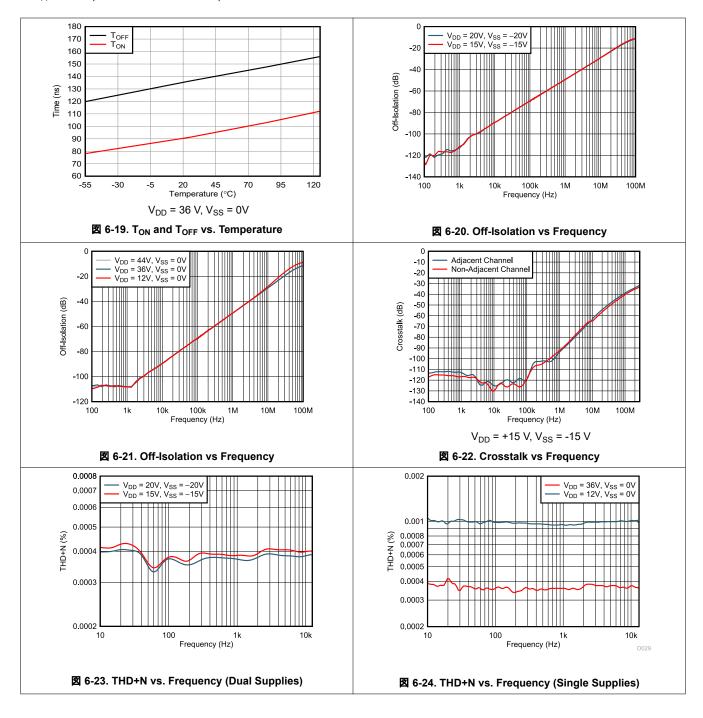


at T<sub>A</sub> = 25°C (unless otherwise noted)





at T<sub>A</sub> = 25°C (unless otherwise noted)



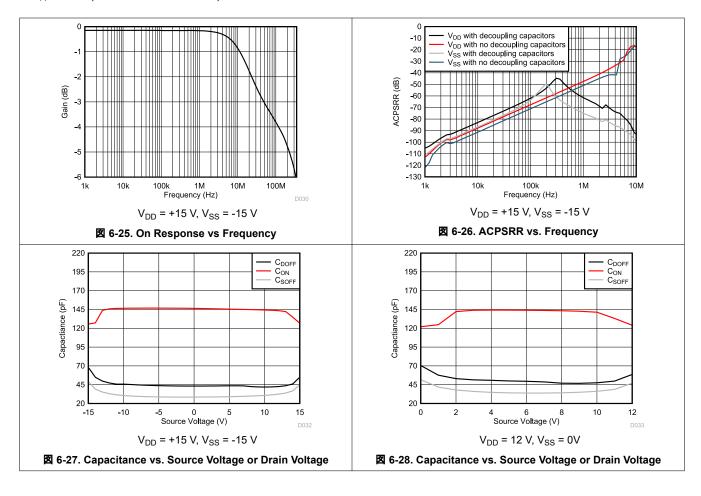
Product Folder Links: TMUX7212M

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at T<sub>A</sub> = 25°C (unless otherwise noted)



## 7 Parameter Measurement Information

#### 7.1 On-Resistance

The on-resistance of a device is the ohmic resistance between the source (Sx) and drain (Dx) pins of the device. The on-resistance varies with input voltage and supply voltage. The symbol R<sub>ON</sub> is used to denote on-resistance. Z 7-1 shows the measurement setup used to measure R<sub>ON</sub>. Voltage (V) and current (I<sub>SD</sub>) are measured using this setup, and  $R_{ON}$  is computed with  $R_{ON} = V / I_{SD}$ :

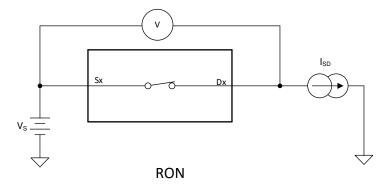


図 7-1. On-Resistance Measurement Setup

## 7.2 Off-Leakage Current

There are two types of leakage currents associated with a switch during the off state:

- 1. Source off-leakage current.
- 2. Drain off-leakage current.

Source leakage current is defined as the leakage current flowing into or out of the source pin when the switch is off. This current is denoted by the symbol I<sub>S(OFF)</sub>.

Drain leakage current is defined as the leakage current flowing into or out of the drain pin when the switch is off. This current is denoted by the symbol I<sub>D(OFF)</sub>.

▼ 7-2 shows the setup used to measure both off-leakage currents.

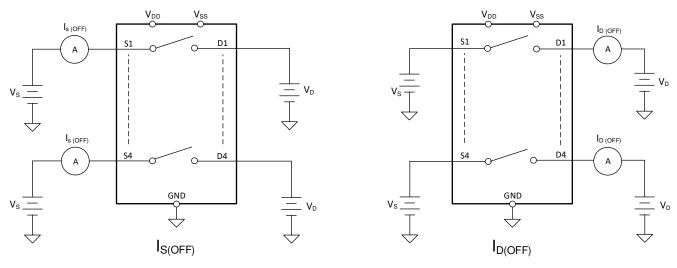


図 7-2. Off-Leakage Measurement Setup

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Product Folder Links: TMUX7212M

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#### 7.3 On-Leakage Current

Source on-leakage current is defined as the leakage current flowing into or out of the source pin when the switch is on. This current is denoted by the symbol I<sub>S(ON)</sub>.

Drain on-leakage current is defined as the leakage current flowing into or out of the drain pin when the switch is on. This current is denoted by the symbol  $I_{D(ON)}$ .

Either the source pin or drain pin is left floating during the measurement.  $\boxtimes$  7-3 shows the circuit used for measuring the on-leakage current, denoted by  $I_{S(ON)}$  or  $I_{D(ON)}$ .

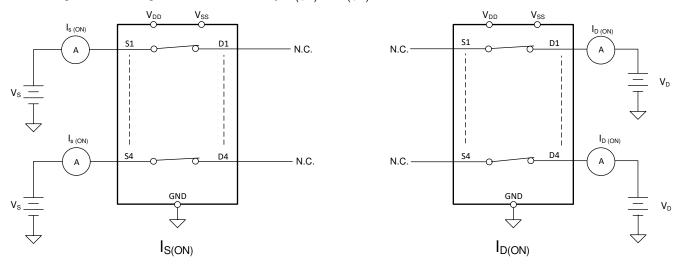


図 7-3. On-Leakage Measurement Setup

## 7.4 t<sub>ON</sub> and t<sub>OFF</sub> Time

Turn-on time is defined as the time taken by the output of the device to rise to 90% after the enable has risen past the logic threshold. The 90% measurement is utilized to provide the timing of the device. System level timing can then account for the time constant added from the load resistance and load capacitance.  $\boxtimes$  7-4 shows the setup used to measure turn-on time, denoted by the symbol  $t_{ON}$ .

Turn-off time is defined as the time taken by the output of the device to fall to 10% after the enable has fallen past the logic threshold. The 10% measurement is utilized to provide the timing of the device. System level timing can then account for the time constant added from the load resistance and load capacitance. 27-4 shows the setup used to measure turn-off time, denoted by the symbol  $t_{OFF}$ .

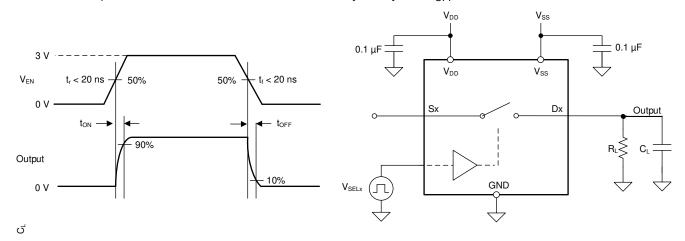


図 7-4. Turn-On and Turn-Off Time Measurement Setup

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## 7.5 t<sub>ON (VDD)</sub> Time

The  $t_{ON\ (VDD)}$  time is defined as the time taken by the output of the device to rise to 90% after the supply has risen past the supply threshold. The 90% measurement is used to provide the timing of the device turning on in the system.  $\boxtimes$  7-5 shows the setup used to measure turn on time, denoted by the symbol  $t_{ON\ (VDD)}$ .

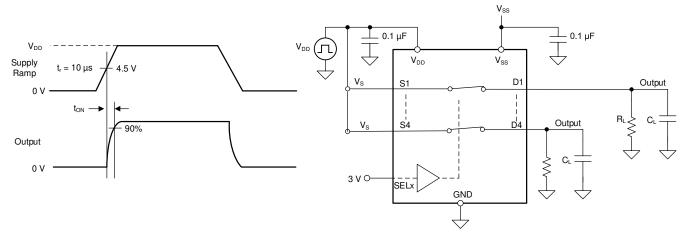


図 7-5. t<sub>ON (VDD)</sub> Time Measurement Setup

## 7.6 Propagation Delay

Propagation delay is defined as the time taken by the output of the device to rise or fall 50% after the input signal has risen or fallen past the 50% threshold.  $\boxtimes$  7-6 shows the setup used to measure propagation delay, denoted by the symbol  $t_{PD}$ .

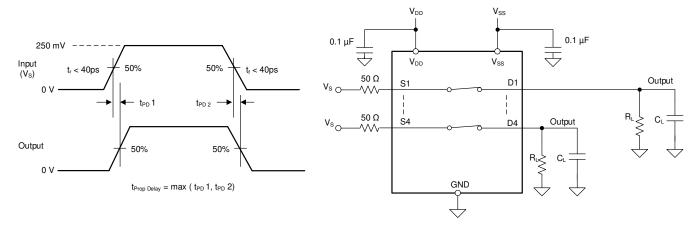


図 7-6. Propagation Delay Measurement Setup

#### 7.7 Charge Injection

The TMUX7212M devices have a transmission-gate topology. Any mismatch in capacitance between the NMOS and PMOS transistors results in a charge injected into the drain or source during the falling or rising edge of the gate signal. The amount of charge injected into the source or drain of the device is known as charge injection, and is denoted by the symbol  $Q_C$ .  $\boxtimes$  7-7 shows the setup used to measure charge injection from source (Sx) to drain (Dx).

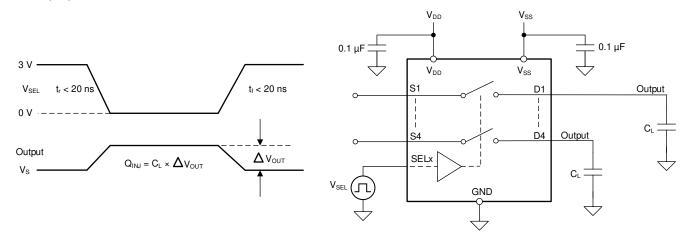


図 7-7. Charge-Injection Measurement Setup

#### 7.8 Off Isolation

Off isolation is defined as the ratio of the signal at the drain pin (Dx) of the device when a signal is applied to the source pin (Sx) of an off-channel. The characteristic impedance,  $Z_0$ , for the measurement is 50  $\Omega$ .  $\boxtimes$  7-8 shows the setup used to measure off isolation. Use off isolation equation to compute off isolation.

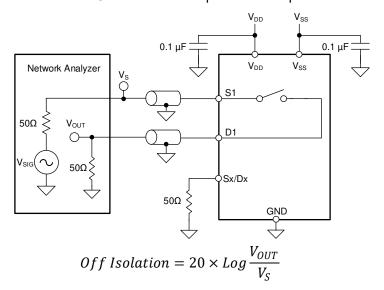


図 7-8. Off Isolation Measurement Setup

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#### 7.9 Channel-to-Channel Crosstalk

Crosstalk is defined as the ratio of the signal at the drain pin (Dx) of a different channel, when a signal is applied at the source pin (Sx) of an on-channel. The characteristic impedance,  $Z_0$ , for the measurement is 50  $\Omega$ .  $\square$  7-9 shows the setup used to measure, and the equation used to compute crosstalk.

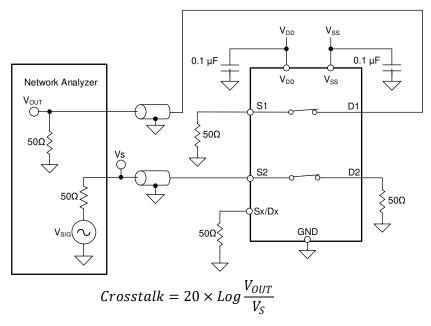


図 7-9. Channel-to-Channel Crosstalk Measurement Setup

#### 7.10 Bandwidth

Bandwidth is defined as the range of frequencies that are attenuated by less than 3 dB when the input is applied to the source pin (Sx) of an on-channel, and the output is measured at the drain pin (Dx) of the device. The characteristic impedance,  $Z_0$ , for the measurement is 50  $\Omega$ .  $\square$  7-10 shows the setup used to measure bandwidth.

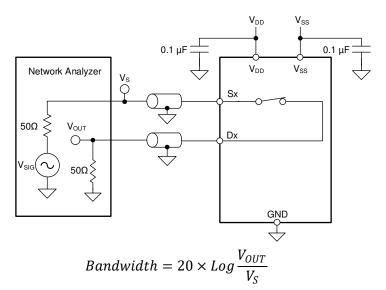


図 7-10. Bandwidth Measurement Setup



#### 7.11 THD + Noise

The total harmonic distortion (THD) of a signal is a measurement of the harmonic distortion, and is defined as the ratio of the sum of the powers of all harmonic components to the power of the fundamental frequency at the mux output. The on-resistance of the device varies with the amplitude of the input signal and results in distortion when the drain pin is connected to a low-impedance load. Total harmonic distortion plus noise is denoted as THD + N.

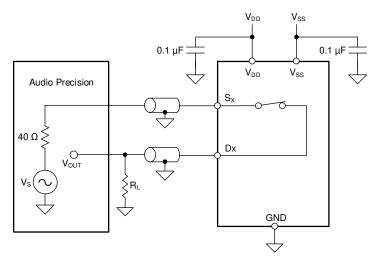


図 7-11. THD + N Measurement Setup

## 7.12 Power Supply Rejection Ratio (PSRR)

PSRR measures the ability of a device to prevent noise and spurious signals that appear on the supply voltage pin from coupling to the output of the switch. The DC voltage on the device supply is modulated by a sine wave of  $100 \text{ mV}_{PP}$ . The ratio of the amplitude of signal on the output to the amplitude of the modulated signal is the AC PSRR.

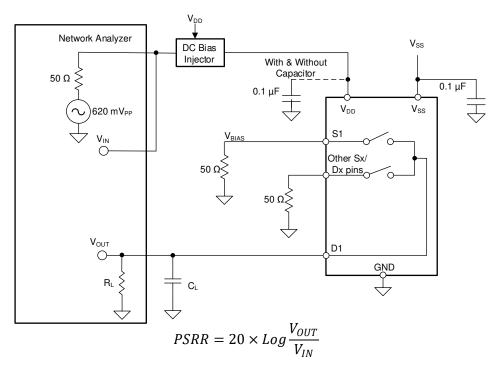


図 7-12. AC PSRR Measurement Setup

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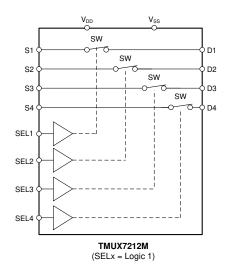
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#### 8 Detailed Description

#### 8.1 Overview

The TMUX7212M is a 1:1 (SPST), 4-channel switch. The device has four independently selectable single-pole, single-throw switches that are turned-on or turned-off based on the state of the corresponding select pin.

## 8.2 Functional Block Diagram



## 8.3 Feature Description

#### 8.3.1 Bidirectional Operation

The TMUX7212M conducts equally well from source (Sx) to drain (Dx) or from drain (Dx) to source (Sx). Each channel has similar characteristics in both directions and supports both analog and digital signals.

#### 8.3.2 Rail-to-Rail Operation

The valid signal path input and output voltage for TMUX7212M ranges from  $V_{SS}$  to  $V_{DD}$ .

#### 8.3.3 1.8V Logic Compatible Inputs

The TMUX7212M device has 1.8V logic compatible control for all logic control inputs. 1.8V logic level inputs allows the TMUX7212M to interface with processors that have lower logic I/O rails and eliminates the need for an external translator, which saves both space and bill of material cost. For more information on 1.8V logic implementations refer to Simplifying Design with 1.8V logic Muxes and Switches.

#### 8.3.4 Integrated Pull-Down Resistor on Logic Pins

The TMUX7212M has internal weak pull-down resistors to GND to ensure the logic pins are not left floating. The value of this pull-down resistor is approximately  $4M\Omega$ , but is clamped to about 1  $\mu$ A at higher voltages. This feature integrates up to four external components and reduces system size and cost.

#### 8.3.5 Fail-Safe Logic

The TMUX7212M supports Fail-Safe Logic on the control input pins (SEL1, SEL2, SEL3, and SEL4) allowing for operation up to 44 V, regardless of the state of the supply pin. This feature allows voltages on the control pins to be applied before the supply pin, protecting the device from potential damage. Fail-Safe Logic minimizes system complexity by removing the need for power supply sequencing on the logic control pins. For example, the Fail-Safe Logic feature allows the select pins of the TMUX7212M to be ramped to 44 V while  $V_{DD}$  and  $V_{SS}$  = 0V. The logic control inputs are protected against positive faults of up to 44 V in powered-off condition, but do not offer protection against negative overvoltage conditions.

Product Folder Links: TMUX7212M

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#### 8.3.6 Latch-Up Immune

Latch-up is a condition where a low impedance path is created between a supply pin and ground. This condition is caused by a trigger (current injection or overvoltage), but once activated, the low impedance path remains even after the trigger is no longer present. This low impedance path may cause system upset or catastrophic damage due to excessive current levels. The latch-up condition typically requires a power cycle to eliminate the low impedance path.

The TMUX7212M family of devices are constructed on silicon on insulator (SOI) based process where an oxide layer is added between the PMOS and NMOS transistor of each CMOS switch to prevent parasitic structures from forming. The oxide layer is also known as an insulating trench and prevents triggering of latch up events due to overvoltage or current injections. The latch-up immunity feature allows the TMUX7212M family of switches and multiplexers to be used in harsh environments. For more information on latch-up immunity refer to Using Latch Up Immune Multiplexers to Help Improve System Reliability.

#### 8.3.7 Ultra-Low Charge Injection

⊠ 8-1 shows how the TMUX7212M devices have a transmission gate topology. Any mismatch in the stray capacitance associated with the NMOS and PMOS causes an output level change whenever the switch is opened or closed.

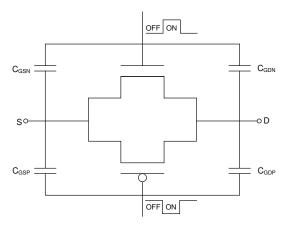


図 8-1. Transmission Gate Topology

The TMUX7212M contains specialized architecture to reduce charge injection on the Drain (Dx). To further reduce charge injection in a sensitive application, a compensation capacitor (Cp) can be added on the Source (Sx). This will ensure that excess charge from the switch transition will be pushed into the compensation capacitor on the Source (Sx) instead of the Drain (Dx). As a general rule, Cp should be 20x larger than the equivalent load capacitance on the Drain (Dx). 8-2 shows charge injection variation with different compensation capacitors on the Source side. This plot was captured on the TMUX7219M as part of the TMUX72xx family with a 100 pF load capacitance.



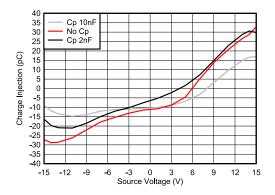


図 8-2. Charge Injection Compensation

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Product Folder Links: TMUX7212M



#### 8.4 Device Functional Modes

The TMUX7212M device has four independently selectable single-pole, single-throw switches that are turned-on or turned-off based on the state of the corresponding select pin. The control pins can be as high as 44 V.

The TMUX7212M devices can operate without any external components except for the supply decoupling capacitors. The SELx pins have internal pull-down resistors of  $4M\Omega$ . If unused, then the SELx pin must be tied to GND for the device to not consume additional current as highlighted in *Implications of Slow or Floating CMOS Inputs*. Unused signal path inputs (Sx or Dx) should be connected to GND.

#### 8.5 Truth Tables

表 8-1 shows the truth tables for the TMUX7212M.

表 8-1. TMUX7212M Truth Table

SEL x <sup>(1)</sup>	CHANNEL x
0	Channel x OFF
1	Channel x ON

(1) x denotes 1, 2, 3, or 4 for the corresponding channel.

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## 9 Application and Implementation

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## 9.1 Application Information

The TMUX7212M is part of the precision switches and multiplexers family of devices. These devices operate with dual supplies ( $\pm 4.5$ V to  $\pm 22$  V), a single supply (4.5V to 44 V), or asymmetric supplies (such as  $V_{DD} = 12$  V,  $V_{SS} = -30$  V), and offer true rail-to-rail input and output. The TMUX7212M offers low  $R_{ON}$ , low on and off leakage currents and ultra-low charge injection performance. These features makes the TMUX7212M a family of precision, robust, high-performance analog multiplexer for high-voltage, automotive applications.

#### 9.2 Typical Application – Switched Gain Amplifier

Switches and multiplexers are commonly used in the feedback path of amplifier circuits to provide configurable gain control. By using various resistor values on each switch path the TMUX7212M allows the system to have multiple gain settings. An external resistor, or utilizing 1 channel always being closed, ensures the amplifier is not operating in an open loop configuration. The leakage current, On-Resistance, and charge injection performance of the TMUX7212M are key specifications to evaluate when selecting a device for gain control.

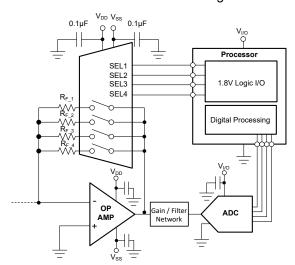


図 9-1. Switching Gain Settings

#### 9.3 Design Requirements

For this design example, use the parameters listed in 表 9-1.

 PARAMETERS
 VALUES

 Supply (V<sub>DD</sub>)
 15 V

 Supply (V<sub>SS</sub>)
 - 15 V

 Input / Output signal range
 -15 V to 15 V (Rail-to-Rail)

 Control logic thresholds
 1.8V compatible

表 9-1. Design Parameters

Product Folder Links: TMUX7212M

English Data Sheet: SCDS456



#### 9.4 Detailed Design Procedure

The TMUX7212M device can be operated without any external components except for the supply decoupling capacitors. All inputs signals passing through the switch must fall within the recommended operating conditions of the TMUX7212M including signal range and continuous current. For this design example, with a supply of +15 V and -15V, the signals can range from +15 V to -15V when the device is powered. The maximum continuous current can be 220mA.

The application shown in *Switching Gain Settings* demonstrates how to use the TMUX7212M to control the feedback gain of a precision op-amp. This feedback design can very sensitive to induced voltage and current offsets. The TMUX7212M has a typical On-leakage current of 100 pA which would lead to an accuracy well within 1% of a full scale 1 µA signal, thus minimizing errors from current offsets. The low On-Resistance of the TMUX7212M leads to a low error in the feedback resistance and resulting gain. This additionally minimizes any voltage offsets.

## 9.5 Power Supply Recommendations

The TMUX7212M device operates across a wide supply range of  $\pm 4.5$ V to  $\pm 22$  V (4.5V to 44 V in single-supply mode). The device also perform well with asymmetrical supplies such as  $V_{DD} = 12$  V and  $V_{SS} = -5$  V.

Power-supply bypassing improves noise margin and prevents switching noise propagation from the supply rails to other components. Good power-supply decoupling is important to achieve optimum performance. For improved supply noise immunity, use a supply decoupling capacitor ranging from  $0.1\mu F$  to  $10\mu F$  at both the  $V_{DD}$  and  $V_{SS}$  pins to ground. Place the bypass capacitors as close to the power supply pins of the device as possible using low-impedance connections. TI recommends using multi-layer ceramic chip capacitors (MLCCs) that offer low equivalent series resistance (ESR) and inductance (ESL) characteristics for power-supply decoupling purposes. For very sensitive systems, or for systems in harsh noise environments, avoiding the use of vias for connecting the capacitors to the device pins may offer superior noise immunity. The use of multiple vias in parallel lowers the overall inductance and is beneficial for connections to ground and power planes. Always ensure the ground (GND) connection is established before supplies are ramped.

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## 9.6 Layout

#### 9.6.1 Layout Guidelines

When a PCB trace turns a corner at a 90° angle, a reflection can occur. A reflection occurs primarily because of the change of width of the trace. At the apex of the turn, the trace width increases to 1.414 times the width. This increase upsets the transmission-line characteristics, especially the distributed capacitance and self–inductance of the trace which results in the reflection. Not all PCB traces can be straight and therefore some traces must turn corners. otin 9-2 shows progressively better techniques of rounding corners. Only the last example (BEST) maintains constant trace width and minimizes reflections.

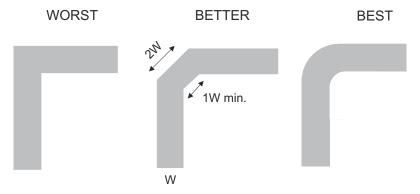


図 9-2. Trace Example

Route high-speed signals using a minimum of vias and corners which reduces signal reflections and impedance changes. When a via must be used, increase the clearance size around it to minimize its capacitance. Each via introduces discontinuities in the signal's transmission line and increases the chance of picking up interference from the other layers of the board. Be careful when designing test points, through-hole pins are not recommended at high frequencies.

#### Some key considerations are:

- For reliable operation, connect a decoupling capacitor ranging from 0.1μF to 10μF between VDD/VSS and GND. We recommend a 0.1μF and 1μF capacitor, placing the lowest value capacitor as close to the pin as possible. Make sure that the capacitor voltage rating is sufficient for the supply voltage.
- · Keep the input lines as short as possible.
- Use a solid ground plane to help reduce electromagnetic interference (EMI) noise pickup.
- Do not run sensitive analog traces in parallel with digital traces. Avoid crossing digital and analog traces if
  possible, and only make perpendicular crossings when necessary.
- Using multiple vias in parallel will lower the overall inductance and is beneficial for connection to ground planes.

#### 9.6.2 Layout Example

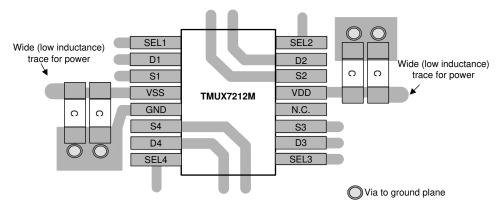


図 9-3. TMUX7212M Layout Example

*資料に関するフィードバック (ご意見やお問い合わせ) を送信* Product Folder Links: *TMUX7212M* 



## 10 Device and Documentation Support

#### **10.1 Documentation Support**

#### 10.1.1 Related Documentation

- Texas Instruments, Using Latch Up Immune Multiplexers to Help Improve System Reliability application note
- · Texas Instruments, Improve Stability Issues with Low CON Multiplexers application brief
- Texas Instruments, Improving Signal Measurement Accuracy in Automated Test Equipment application brief
- Texas Instruments, Sample & Hold Glitch Reduction for Precision Outputs Reference Design reference guide
- Texas Instruments, Simplifying Design with 1.8V logic Muxes and Switches application brief
- Texas Instruments, System-Level Protection for High-Voltage Analog Multiplexers application note
- Texas Instruments, *True Differential, 4 x 2 MUX, Analog Front End, Simultaneous-Sampling ADC Circuit* application note
- Texas Instruments, Quad Flatpack No-Lead Logic Packages application note

## 10.2 ドキュメントの更新通知を受け取る方法

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#### 10.5 静電気放電に関する注意事項



この IC は、ESD によって破損する可能性があります。テキサス・インスツルメンツは、IC を取り扱う際には常に適切な注意を払うことを推奨します。正しい取り扱いおよび設置手順に従わない場合、デバイスを破損するおそれがあります。

ESD による破損は、わずかな性能低下からデバイスの完全な故障まで多岐にわたります。精密な IC の場合、パラメータがわずかに変化するだけで公表されている仕様から外れる可能性があるため、破損が発生しやすくなっています。

## 10.6 用語集

テキサス・インスツルメンツ用語集 この用語集には、用語や略語の一覧および定義が記載されています。

#### 11 Revision History

DATE	REVISION	NOTES
January 2024	*	Initial Release

#### 12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

資料に関するフィードバック(ご意見やお問い合わせ)を送信

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#### PACKAGING INFORMATION

Orderable part number	Status (1)	Material type	Package   Pins	Package qty   Carrier	<b>RoHS</b> (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
TMUX7212MPWR	Active	Production	TSSOP (PW)   16	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	X212
TMUX7212MPWR.B	Active	Production	TSSOP (PW)   16	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	X212

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

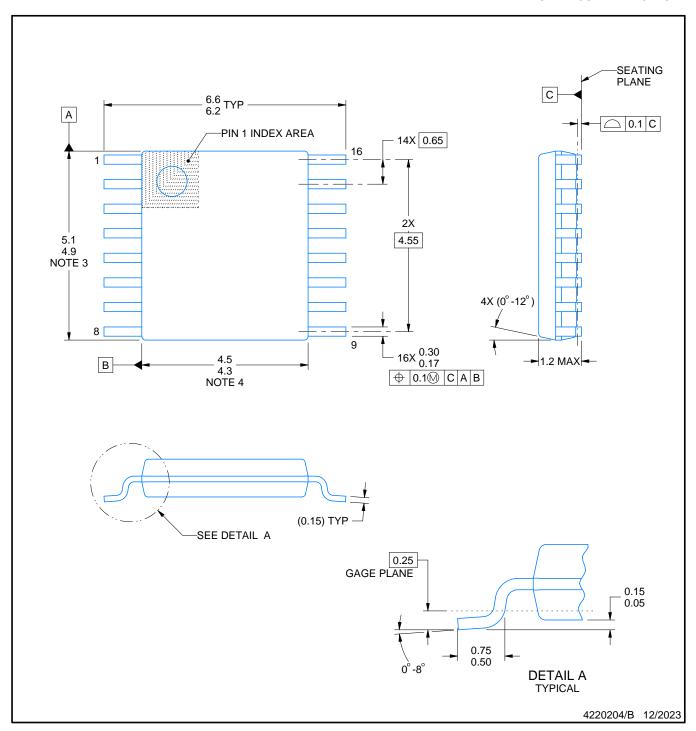
<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



SMALL OUTLINE PACKAGE



#### NOTES:

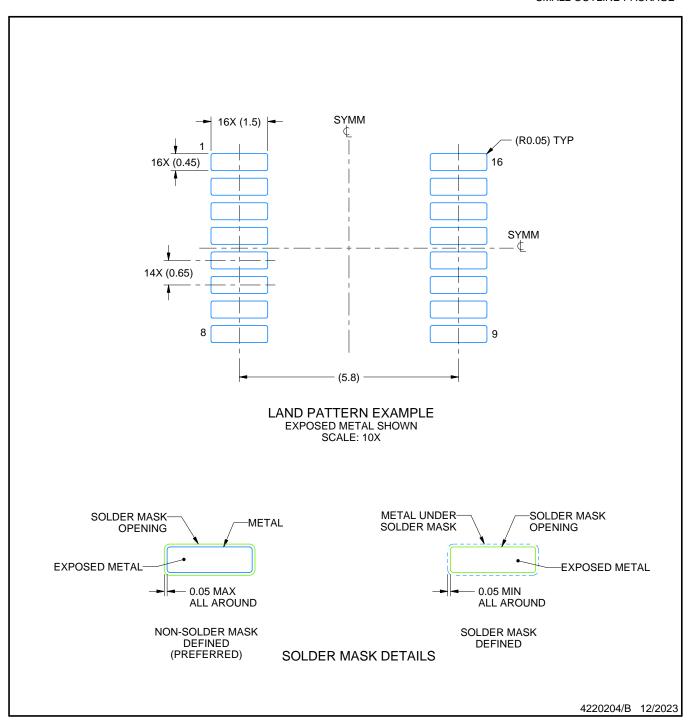
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE

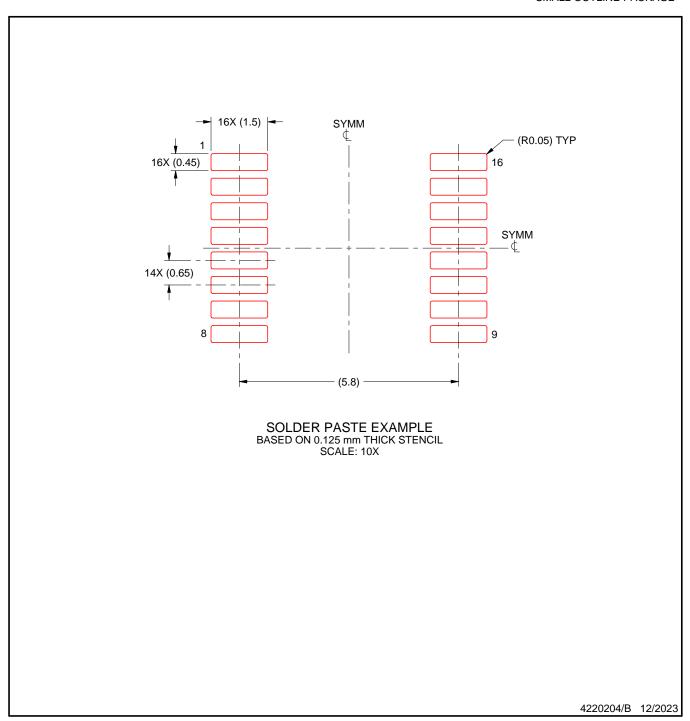


NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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